

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-019002	Application No. 09/126,826
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki, et al.	
		Filing Date July 31, 1998	Group Art Unit 2871

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
DN	AA	3,896,430	07/22/1975	Hatsukano	345	053	11/27/1973
	AB	4,065,781	12/27/1977	Gutknecht	257	066	06/21/1974
	AC	4,068,020	01/10/1978	Reuschel	438	482	12/29/1975
	AD	4,103,297	07/25/1978	McGreivy et al.	345	090	12/20/1976
	AE	4,239,346	12/16/1980	Lloyd	349	044	05/23/1979
	AF	4,365,013	12/21/1982	Ishioka et al.	430	57.5	07/28/1981
	AG	4,378,417	03/29/1983	Maruyama et al.	430	57.5	04/15/1981
	AH	4,470,060	09/04/1984	Yamazaki	349	046	01/11/1982
	AI	4,569,903	02/11/1986	Hashiue et al.	430	350	10/25/1984
	AJ	4,582,395	04/15/1986	Morozumi	349	043	07/30/1981
	AK	4,591,892	05/27/1986	Yamazaki	257	458	08/22/1983
	AL	4,597,160	07/01/1986	Ipri	438	166	08/09/1985
	AM	4,609,930	09/02/1986	Yamazaki	257	059	05/07/1984
	AN	4,668,969	05/26/1987	Yamazaki	257	058	07/23/1984
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	AP	4,740,829	04/26/1988	Nakagiri et al.	257	065	12/03/1986
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	AW	4,862,237	08/29/1989	Morozumi	257	072	10/04/1988
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DN	BA	4,897,360	01/30/1990	Guckel et al.	216	002	12/09/1987

Examiner Signature <i>DN WYEN</i>	Date Considered <i>08/17/05</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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	BH	4,969,025	11/06/1990	Yamamoto et al.	257	056	09/25/1989
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	BK	5,003,356	03/26/1991	Wakai et al.	257	390	04/02/1990
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	BM	5,032,883	07/16/1991	Wakai et al.	257	059	09/07/1988
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	BO	5,054,887	10/08/1991	Kato et al.	349	042	08/09/1989
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	BS	5,077,223	12/31/1991	Yamazaki	438	027	11/29/1989
	BT	5,084,905	01/28/1992	Sasaki et al.	257	776	10/02/1989
	BU	5,085,973	02/04/1992	Shimizu et al.	430	271.1	06/13/1991
	BV	5,107,308	04/21/1992	Koezuka et al.	257	040	06/29/1987
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	BZ	5,247,191	09/21/1993	Yamazaki et al.	257	072	08/01/1991
	CA	5,250,818	10/05/1993	Saraswat et al.	257	066	03/01/1991
DN	CB	5,250,931	10/05/1993	Misawa et al.	345	206	05/15/1989

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	CD	5,289,300	02/22/1994	Yamazaki et al.	349	042	02/03/1992
	CE	5,304,895	04/19/1994	Ujihara	315	072	07/02/1992
	CF	5,327,001	07/05/1994	Wakai et al.	257	250	04/01/1993
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	CH	5,346,850	09/13/1994	Kaschmitter et al.	438	487	10/29/1992
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	CK	5,403,756	04/04/1995	Yoshinouchi et al.	438	162	11/24/1993
	CL	5,427,961	06/27/1995	Takenouchi et al.	438	096	02/19/1993
	CM	5,453,350	09/26/1995	Kurachi et al.	430	527	06/30/1994
	CN	5,456,763	10/10/1995	Kaschmitter et al.	136	258	03/29/1994
	CO	5,470,619	11/28/1995	Ahn et al.	438	479	07/29/1994
	CP	5,470,681	11/28/1995	Brunner et al.	430	005	12/23/1993
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	CS	5,498,573	03/12/1996	Whetten	438	644	06/12/1992
	CT	5,500,537	03/19/1996	Tsumura et al.	257	066	07/30/1993
	CU	5,529,951	06/25/1996	Noguchi et al.	349	041	11/01/1994
	CV	5,530,265	06/25/1996	Takemura	257	066	08/05/1994
	CW	5,535,027	07/09/1996	Kimura et al.	349	041	06/28/1994
	CX	5,541,748	07/30/1996	Ono et al.	349	042	06/07/1994
	CY	5,612,799	03/18/1997	Yamazaki et al.	349	042	10/13/1995
	CZ	5,627,404	05/06/1997	Takenouchi et al.	257	642	02/13/1995
	DA	5,631,753	05/20/1997	Hamaguchi et al.	349	110	04/14/1993
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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	DE	5,744,818	04/28/1998	Yamazaki et al.	257	057	04/25/1995
	DF	5,747,928	05/05/1998	Shanks et al.	313	498	10/07/1994
	DG	5,776,803	07/07/1998	Young	438	149	10/15/1996
	DH	5,933,205	08/03/1999	Yamazaki et al.	349	043	06/26/1998
	DI	6,049,364	04/11/2000	Takahara et al.	349	010	01/27/1997
	DJ	6,242,758	06/05/2001	Yamazaki et al.	257	059	10/22/1997
	DK	6,429,053	08/06/2002	Yamazaki et al.	438	149	11/03/1997
	DL	2004/0183076	09/23/2004	Yamazaki et al.	257	072	04/02/2004
	DM	2004/0183077	09/23/2004	Yamazaki et al.	257	072	04/02/2004
	DN	2004/0211962	10/28/2004	Yamazaki et al.	257	066	05/25/2004
	DO	2005/0020002	01/27/2005	Yamazaki et al.	438	202	08/26/2004
DN	DP	2005/0045884	03/03/2005	Yamazaki et al.	257	066	05/25/2004

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							Yes No
DN	DQ	EP 231953	08/12/1987	JAPAN	-	-	In English
	DR	JP 53-144297	12/15/1978	JAPAN	-	-	Abstract
	DS	JP 55-032026	03/06/1980	JAPAN	-	-	Full
	DT	JP 60-033863	02/21/1985	JAPAN	-	-	Abstract
	DU	JP 60-035574	02/23/1985	JAPAN	-	-	Abstract
	DV	JP 60-066863	04/17/1985	JAPAN	-	-	Abstract
	DW	JP 60-066865	04/17/1985	JAPAN	-	-	Abstract
	DX	JP 61-141174	06/28/1986	JAPAN	-	-	Full
	DY	JP 63-100777	05/02/1988	JAPAN	-	-	Abstract
	DZ	JP 63-279228	11/16/1988	JAPAN	-	-	Full
DN	EA	JP 64-030272	02/01/1989	JAPAN	-	-	Abstract

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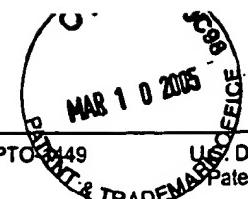
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							Yes No
DN	EB	JP 64-068724	03/14/1989	JAPAN	—	—	Abstract
	EC	JP 01-130131	05/23/1989	JAPAN	—	—	Abstract
	ED	JP 01-156725	06/20/1989	JAPAN	—	—	Full
	EE	JP 02-051129	02/21/1990	JAPAN	—	—	Abstract
	EF	JP 02-103925	04/17/1990	JAPAN	—	—	Abstract
	EG	JP 02-188723	07/24/1990	JAPAN	—	—	Abstract
	EH	JP 02-234134	09/17/1990	JAPAN	—	—	Full
	EI	JP 04-184424	07/01/1992	JAPAN	—	—	Abstract
DN	EJ	JP 06-163958	06/10/1994	JAPAN	—	—	Abstract

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bw	EL	Yeh et al., "Novel Technique For SiO ₂ Formed By Liquid-Phase Deposition For Low-Temperature Processed Polysilicon TFT", IEEE Electron Device Letters, Vol. 14, No. 8, 1993, PP. 403-405.
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Sheet 1 of 1

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	AL	05-040278	02/1993	JAPAN			ABS	
	AM	05-232494	09/1993	JAPAN			ABS	
	AN	06-075244	03/1994	JAPAN			ABS	
	AO	06-258661	09/1994	JAPAN			ABS	
	AP	06-347825	12/1994	JAPAN			ABS	
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